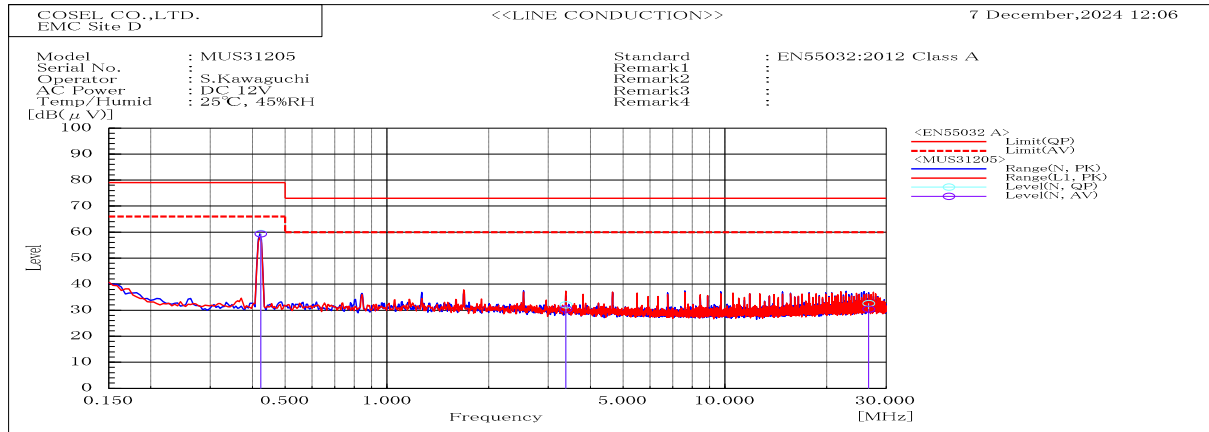
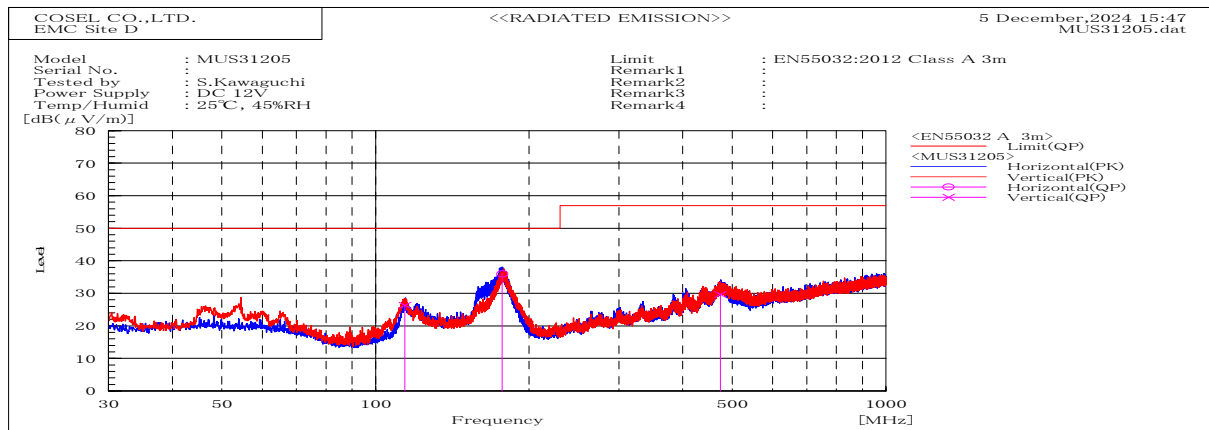


## DATA SHEET

DATA SHEET			Date	07-Dec-24
Model	MUS31205		Temp.	25 degreeC
Test	EMI		Humid.	45 %RH
	Line conduction & Radiated emission		Tested by	S.Kawaguchi



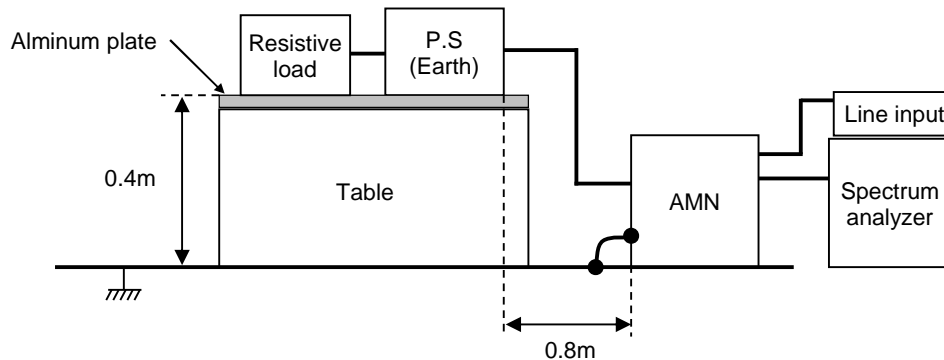
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.423	N	59.5	59.3	79	66	19.5	6.7	Pass	
26.654	N	32.6	30.4	73	60	40.4	29.6	Pass	
3.384	N	32.1	30.4	73	60	40.9	29.6	Pass	



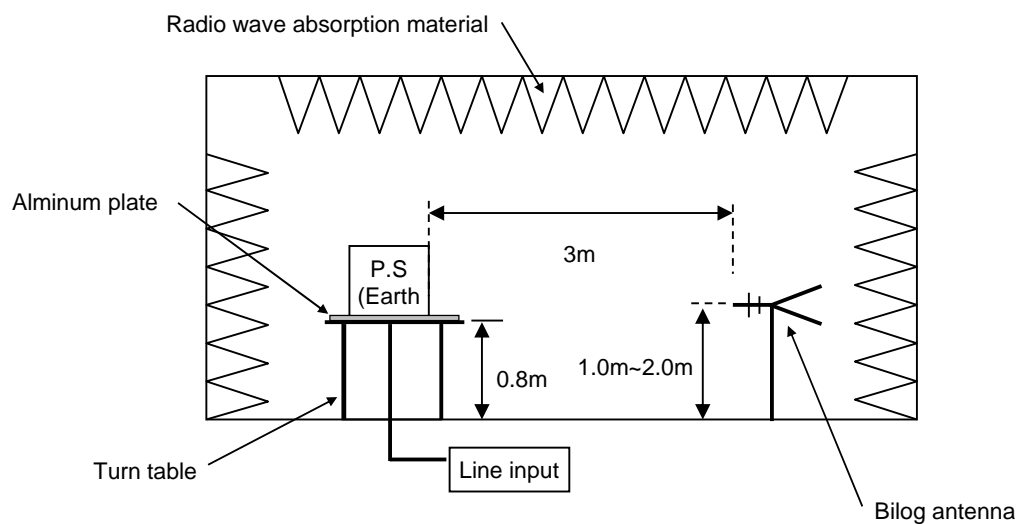
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
177.162	H	Stable	36	50	14	Pass	200	43.4	
114.149	V	Stable	26.3	50	23.7	Pass	100.2	336.3	
474.022	V	Stable	29.7	57	27.3	Pass	100.4	4.5	

DATA SHEET		Date	07-Dec-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

### 1. Line conduction



### 2. Radiated emission



## Conditions

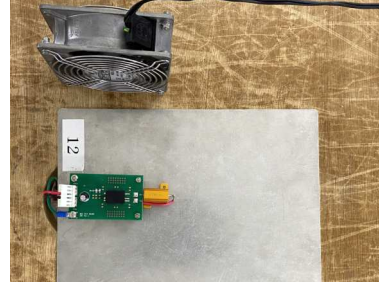
Test : EMI  
Model Name: MUS3□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

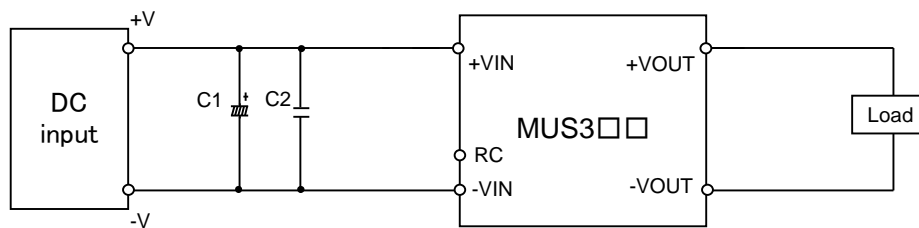


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 $\mu$ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 $\mu$ F	Ceramic capacitor (C3216X7R1H106KT TDK)

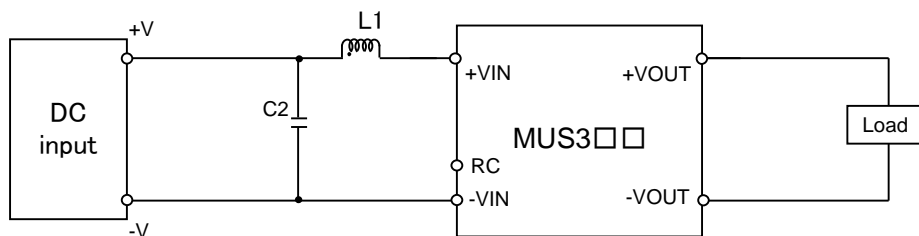


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 $\mu$ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)